Product data sheet

1. General description

Planar passivated high commutation three quadrant triac in a TO220 plastic package. This triac is intended for use in motor control circuits where high blocking voltage, high static and dynamic dV_D/dt as well as high dI_{com}/dt can occur. This "series C0T" triac will commutate the full rated RMS current at the maximum rated junction temperature without the aid of a snubber. This device has high operating capability ($T_{i(max)} = 150~{\rm ^{\circ}C}$).

2. Features and benefits

- · 3Q technology for improved noise immunity
- High commutation capability with maximum false trigger immunity
- High junction operating temperature capability (T_{i(max)} = 150 °C)
- High immunity to false turn-on by dV/dt
- High voltage capability
- · Less sensitive gate for very high noise immunity
- Planar passivated for voltage ruggedness and reliability
- Triggering in three quadrants only

3. Applications

- Applications subject to high temperature (T_{i(max)} = 150 °C)
- · Compressor starting control circuits
- General purpose motor controls
- Reversing induction motor controls e.g. vertical axis washing machines

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Notes	Values		Unit			
Absolute maximum rating									
V_{DRM}	repetitive peak off-state voltage				800		V		
I _{T(RMS)}	RMS on-state current	full sine wave; $T_{mb} \le 134 ^{\circ}\text{C}$; Fig. 1; Fig. 2; Fig. 3			8		А		
I _{TSM}	non-repetitive peak on- state current	full sine wave; $T_{j(init)}$ = 25 °C; t_p = 20 ms; Fig. 4; Fig. 5		60			А		
		full sine wave; $T_{j(init)}$ = 25 °C; t_p = 16.7 ms			65		Α		
T _j	operating junction temperature			-	40 to 15	0	°C		
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit		
Static ch	aracteristics								
I _{GT}	gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G+;$ $T_j = 25 \text{ °C}; Fig. 7$		5	-	50	mA		
		$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G-;$ $T_j = 25 \text{ °C}; Fig. 7$		5	-	50	mA		
		$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2- G-;$ $T_j = 25 \text{ °C}; Fig. 7$		5	-	50	mA		

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>		-	-	60	mA
V _T	on-state voltage	I _T = 10 A; T _j = 25 °C; <u>Fig. 10</u>		-	1.30	1.65	V
Dynamic	characteristics		'	,	'		
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 536 V; T_{j} = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit		2000	-	-	V/µs
		V_{DM} = 536 V; T_j = 150 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit		1500	-	-	V/µs
dI _{com} /dt	rate of change of commutating current	$V_D = 400 \text{ V; } T_j = 125 \text{ °C; } I_{T(RMS)} = 8 \text{ A;}$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s; (snubberless condition); gate open circuit; Fig. 12}$		15	-	-	A/ms
		$V_D = 400 \text{ V; } T_j = 150 \text{ °C; } I_{T(RMS)} = 8 \text{ A;}$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s; (snubberless condition); gate open circuit; Fig. 12}$		7	-	-	A/ms

5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	T1	main terminal 1	mb	N
2	T2	main terminal 2	2	T2 T1
3	G	gate		sym051
mb	T2	mounting base; main terminal 2		

6. Ordering information

Table 3. Ordering information

Type number	pe number Package Orderable p		Packing	Small packing	Package	Package					
	name		method	quantity	version	issue date					
BTA308-800B0T	TO220	BTA308-800B0TQ	Tube	50	SOT78	13-Jun-2008					

7. Marking

Table 4. Marking codes

Type number	Marking codes
BTA308-800B0T	BTA308 800B0T

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Notes	Values	Unit
V_{DRM}	repetitive peak off-state voltage			800	V
I _{T(RMS)}	RMS on-state current	full sine wave; T _{mb} ≤ 134 °C; Fig. 1; Fig. 2; Fig. 3		8	А
I _{TSM}	non-repetitive peak on- state current	full sine wave; $T_{j(init)}$ = 25 °C; t_p = 20 ms; Fig. 4; Fig. 5		60	А
		full sine wave; $T_{j(init)}$ = 25 °C; t_p = 16.7 ms		65	А
l ² t	I ² t for fusing	t _p = 10 ms; SIN		18	A ² s
dl _⊤ /dt	rate of rise of on-state current	I _G = 100 mA		100	A/µs
I _{GM}	peak gate current			2	А
P_{GM}	peak gate power			5	W
$P_{G(AV)}$	average gate power	over any 20 ms period		0.5	W
T _{stg}	storage temperature			-40 to 150	°C
T _j	operating junction temperature			-40 to 150	°C

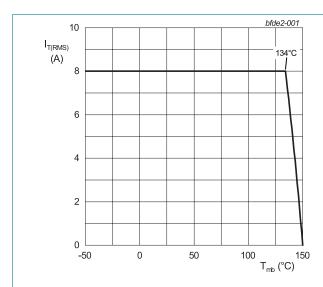
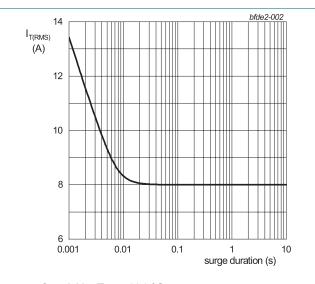
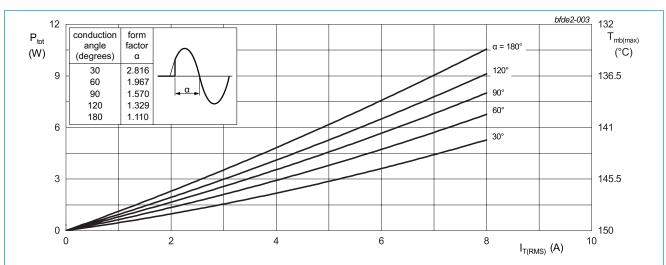


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values



f = 50 Hz; $T_{mb} = 134 \text{ °C}$

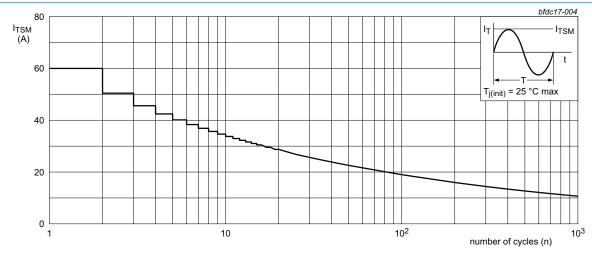
Fig. 2. RMS on-state current as a function of surge duration; maximum values



 α = conduction angle

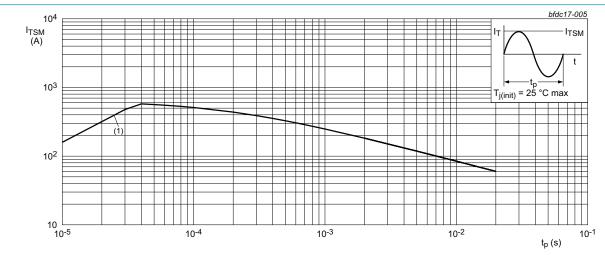
a = form factor = $I_{T(RMS)}$ / $I_{T(AV)}$

Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values



f = 50 Hz

Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values



 $t_p \le 20 \text{ ms}$

(1) dI_T/dt limit

Fig. 5. Non-repetitive peak on-state current as a function of pulse duration; maximum values

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9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-mb)}	thermal resistance from junction to mounting base	Fig. 6	-	-	1.5	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient	in free air	-	60	-	K/W

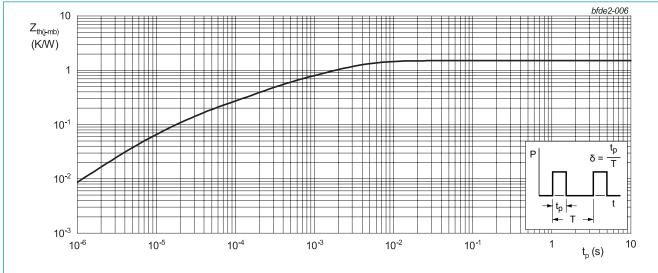
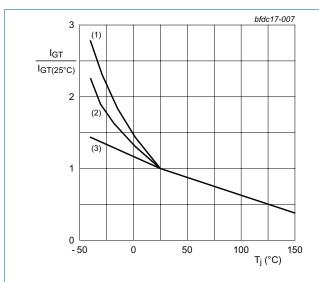


Fig. 6. Transient thermal impedance from junction to mounting base as a function of pulse width

11. Characteristics

Table 8. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static ch	aracteristics					
I _{GT}	gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G+;$ $T_j = 25 \text{ °C}; Fig. 7$	5	-	50	mA
		$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ \text{ G-};$ $T_j = 25 \text{ °C}; Fig. 7$	5	-	50	mA
		$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2- \text{G-};$ $T_j = 25 \text{ °C}; Fig. 7$	5	-	50	mA
l _L	latching current	$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ G+;$ $T_j = 25 \text{ °C}; Fig. 8$	-	-	60	mA
		$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ \text{ G-};$ $T_j = 25 \text{ °C}; Fig. 8$	-	-	90	mA
		$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; \text{ T2- G-};$ $T_j = 25 \text{ °C}; \frac{\text{Fig. 8}}{2}$	-	-	60	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>	-	-	60	mA
V _T	on-state voltage	I _T = 10 A; T _j = 25 °C; <u>Fig. 10</u>	-	1.30	1.65	V
V_{GT}	gate trigger voltage	V _D = 12 V; I _T = 0.1 A; T _j = 25 °C; <u>Fig. 11</u>	-	0.7	1	V
		V _D = 400 V; I _T = 0.1 A; T _j = 150 °C	0.2	0.45	-	V
I _D	off-state current	V _D = 800 V; T _j = 25 °C	-	-	10	μA
		V _D = 800 V; T _j = 150 °C	-	-	1	mA
I _R	reverse current	V _D = 800 V; T _j = 25 °C	-	-	10	μΑ
		V _D = 800 V; T _j = 150 °C	-	-	1	mA
Dynamic	characteristics			'		
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 536 V; T_{j} = 125 °C; $(V_{DM}$ = 67% of V_{DRM}); exponential waveform; gate open circuit	2000	-	-	V/µs
		V_{DM} = 536 V; T_j = 150 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit	1500	-	-	V/µs
dI _{com} /dt	rate of change of commutating current	$V_D = 400 \text{ V; } T_j = 125 \text{ °C; } I_{T(RMS)} = 8 \text{ A;}$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s; (snubberless condition); gate open circuit; Fig. 12}$	15	-	-	A/ms
		$V_D = 400 \text{ V; } T_j = 150 \text{ °C; } I_{T(RMS)} = 8 \text{ A;}$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s; (snubberless condition); gate open circuit; Fig. 12}$	7	-	-	A/ms



- (1) T2- G-
- (2) T2+ G-
- (3) T2+ G+

Fig. 7. Normalized gate trigger current as a function of junction temperature

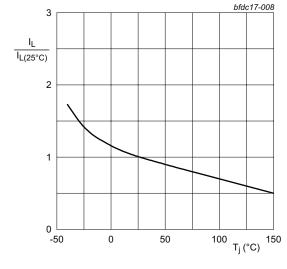


Fig. 8. Normalized latching current as a function of junction temperature

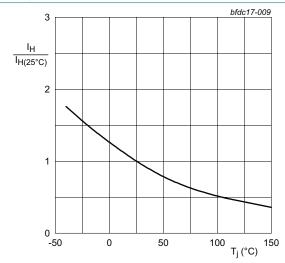
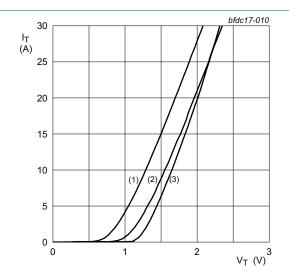


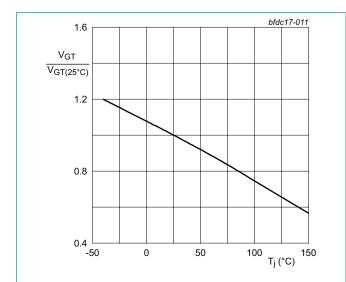
Fig. 9. Normalized holding current as a function of junction temperature



 V_o = 1.210 V; R_s = 0.0288 Ω

(1) $T_j = 150 \,^{\circ}\text{C}$; typical values (2) $T_j = 150 \,^{\circ}\text{C}$; maximum values (3) $T_j = 25 \,^{\circ}\text{C}$; maximum values

Fig. 10. On-state current as a function of on-state voltage





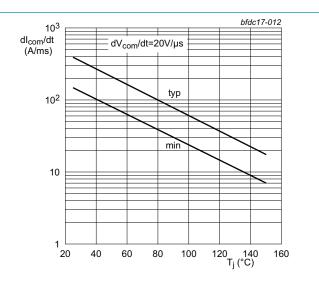
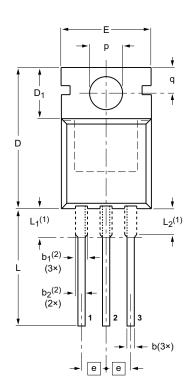
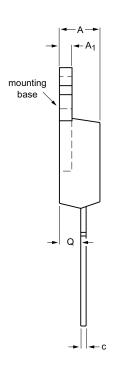


Fig. 12. Rate of change of commutating current as a function of junction temperature; typical and minimum values

12. Package outline







0 5 10 mm

DIMENSIONS (mm are the original dimensions)

UNIT	Α	A ₁	b	b ₁ ⁽²⁾	b ₂ ⁽²⁾	С	D	D ₁	E	е	L	L ₁ ⁽¹⁾	L ₂ ⁽¹⁾ max.	р	q	Q
mm	4.7 4.1	1.40 1.25	0.9 0.6	1.6 1.0	1.3 1.0	0.7 0.4	16.0 15.2	6.6 5.9	10.3 9.7	2.54	15.0 12.8	3.30 2.79	3.0	3.8 3.5	3.0 2.7	2.6 2.2

Notes

- 1. Lead shoulder designs may vary.
- 2. Dimension includes excess dambar.

OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE	
SOT78		3-lead TO-220AB	SC-46		08-04-23 08-06-13	

13. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
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